

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

## LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

ATTORNEY DOCKET NO.  
392.1893APPLICATION NO.  
TBA 10/826322FIRST NAMED INVENTOR  
Michiya INOUE, et al.FILING DATE  
April 19, 2004GROUP ART UNIT  
TBA 2193

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO
/J.W./	AG	05-313708	11/26/93	Japan			abs
/J.W./	AH	2002-358102	12/13/02	Japan			abs
	AI						
	AJ						
	AK						
	AL						

## OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

			TRANSLATION YES NO
	AM		
	AN		
	AO		

EXAMINER /Jue Wang/ DATE CONSIDERED 09/25/2007

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Sheet 1 of 1

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				392.1893	10/826,322
				FIRST NAMED INVENTOR	
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**INFORMATION DISCLOSURE STATEMENT**  
(Use several sheets if necessary)

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
/J.W./	AA	6,810,433	10-2004	Nishimaki et al.			
	AB						
	AC						
	AD						
	AE						
	AF						

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NO.	DATE	COUNTRY	TRANSLATION YES	TRANSLATION NO	ABSTRACT
/J.W./	AG	08-054913	02-1996	Japan			X
/J.W./	AH	11-085229	03-1999	Japan			X
/J.W./	AI	2003-058210	02-2003	Japan			X
/J.W./	AJ	09-152905	06-1997	Japan			X
/J.W./	AK	00/43883	07-2000	WO		X	
	AL	--					

**OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)**

			TRANSLATION YES	TRANSLATION NO
/J.W./	AM	Notification of Grounds for Rejection (Office Action) in corresponding Japanese Patent Application 115753/2003	X	

EXAMINER	DATE CONSIDERED
/Jue Wang/	09/25/2007

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